Physical resolution limits of single particle 3D imaging with X-rays and electrons

Coherence 2005 Dirk Van Dyck and Sandra Van Aert June 15, 2005



Ultimate goal: imaging of atoms

- Understanding properties of nanostructures
 - biological structures
 - (in)organic materials
 - components
- > Matching experiment with theoretical, ab initio calculations
- Modelling
- Predicting and designing nanostructures



What is needed to match experiment with ab initio theory?

- 1. Precise atomic positions (±0.001 nm)
- 2. Complementary information
 - Prior information (e.g. substructures)
 - Local spectroscopic information
 - chemical
 - bonding
 - electronic structure
 - local configuration



How to characterize atomic structures?

- Interaction with particles
 - photons (X-rays)
 - electrons
 - neutrons
 - protons
- Requirements
 - bright coherent sources
 - easy to detect
 - subångstrom wavelength



X-rays (XDM, XD) and electrons (EM, ED, EDI)



Quantitative experiment



- Detection of individual particles
- Model based fitting



model space

simulation

experiments

and the second





refinement



Observations

- number of particles hitting detector i (e.g. pixel in CCD)
 - stochastic variables

$$\sum_{i} n_i = N$$

<u>Model</u>

 $E[n_i] = Np_i(\theta_k)$

- p_i probability to hit pixel i
- θ_k model parameters
- structural parameters (atomic positions,...)
 - instrumental parameters (fixed and tunable)



Requirements

- The model contains all ingredients needed to perform a simulation (structure, interaction, instrument, detection)
- The model is assumed to be correct
- The experiment is the ensemble of all experiments (focal images, tomographic series, DP,...)
- Only fitting with original experimental data (noise model)



Maximum likelihood estimator

- Lowest possible error bar (CRLB)
- Unbiased

Likelihood function

$$L = N! \prod_{i} \frac{p_i^{n_i}(\theta_k)}{n_i!}$$
$$\ln L = \sum_{i} n_i p_i(\theta_k) + C$$

Maximum likelihood

$$\frac{\partial \ln L}{\partial \theta_k} = 0 \quad \forall k \quad \Rightarrow \text{ estimates } \hat{\theta}_k$$



Error bar on the estimated parameters

 σ_i^2 : variance of estimated parameter θ_i

Then

$$\sigma_i^2 \ge -E \left[\frac{\partial^2 \ln L}{\partial \theta_k \partial \theta_l} \right]_{ii}^{-1}$$







Resolution - precision



The dose can be distributed over many images (dose fractionation theorem)



model space

simulation

experiments





		の語言
		(1) (1) (2) (2) (2) (2) (2) (2) (2) (2) (2) (2

refinement

Iteration till best fit



Problems: - convergence

- local optima
- uniqueness



How to avoid local optima?

1) "Resolving" the structure

Obtain a good starting structure using general principles

- Direct imaging
- Image reconstruction
- Direct methods (phase constraints)
- Constrained optimisation: hybrid I-O
- 2) "Refining" the structure

Convergence to global optimum (maximum likelihood)



Focus variation reconstruction





Phase of total exit wave Σ 5 AI: Cu



Courtesy C. Kisielowski (NCEM, Berkeley)







ELECTRON MICRO IFF/IMF C.L. Jia and A. Thust, Phys. Rev. Lett. 82 (1999) 5052.



Comparison: Theory & Experiment

	Ti-Ti [pm]	Ba - Ba [pm]		
Geometric	232	232		
Experiment	270	216		
Theory	267	214		

Plane Distances at Σ 3(111) Twin Boundary

Charge Density from First Principles Calculation:



Ti-Ti: 4.5 x $10^{-2} e / a.u.^3$ 3 x $10^{-2} e / a.u.^3$ ELECTRON MICROSCOPY FOR MATERIALS SCIENCE /a.u.³ 9 x 10⁻³ e /a.u.³



Uniqueness problem

If number of parameters exceeds information capacity of imaging channel



3D Tomography



 $P/a^{3} < 4/\rho^{3}$

Information content = 4 parameters per ρ^3

2 angstrom resolution sufficient in 3D



HREM of amorphous structures

resolution = 1A





Required dose

Rose criterion





Limitations of resolution



Sufficient brightness, time, stability of specimen (inorganic objects)

> Resolution limited by the instrument ultimate resolution = atom



•Insufficient brightness, time

•Instability of specimen (radiation damage) (life-science objects)

"object resolution"



Knock-on damage (inorganic objects)

Inelastic cross section<elastic cross section resolution = atom

<u>Ionisation damage</u> (life science objects) Instrument resolution < object resolution



Atomic resolution EM

Point-spread function:







ultimate resolution = intrinsic width of the atom

image same information as DP (2x)

Note knock-on damage: cross section smaller than P_A





amorphous Ge



Example: amorphous tungsten

Number of atoms used: 1859

 $C_s = 0.5 \text{ mm}$ E = 300 keV $\epsilon = -1.15 \text{ Sch}$

180 images with 1° increment

Dose/image = 1.4×10^4 Å⁻²







Cs = 0.05 mm



Number of atoms used: 1859

 $C_s = 0.5 \text{ mm}$ E = 300 keV $\epsilon = -1.15 \text{ Sch}$

180 images with 1° increment Dose/image = $1.4 \times 10^4 \text{ Å}^{-2}$

First atomic-resolution diffractive image reconstruction.

Double-walled Nanotube



Image reconstructed from electron-diffraction pattern by HiO



ELECTRON MICROSCOPY FOR MATERIALS SCIENCE

J.M.Zuo et al Science 300, 1420 (2003).

Object resolution for life-science objects



Resolution-dose for life-science objects





How to improve object resolution?

- Radiation damage
 - □ Electrons better than X-rays
 - □ Tune energy
 - □ Cryo protection
 - Averaging over identical objects
 - □ Inertial imaging (FELS)
- Fitting known substructures
 - □ Small proteins
 - □ Alpha helices
 - Beta sheets
- Specimen preparation (FIB, DIP-PEN)



	Electrons 80–500 keV			Neutrons		
		×		1-8Å	1-8Å 0-01	
		Electrons	A-rays	⁴ H. ¹⁴ N	"H, 18N	
		1°5 Å	1-5 Å 30 Å labelled	labelled (99%)		
Ratio † (inelastic/elastic) scattering events	3	10	102-104	0.080	0.001	10-8
Mechanism of radiation damage	Secondary e ⁻ emission	Photoel e" emis	ectric ssion	${}^{1}H(n, \gamma) \rightarrow {}^{4}H$ ${}^{14}N(n, p) \rightarrow {}^{14}C$ and recoil energy	Variety o cross-sec reaction: as residu ¹ H, ¹⁴ N	f lower ction s as well aal
Energy deposited per inelastic event	20 eV	8 keV	400 eV	2 keV*	z keV*	2 KeV*
Energy deposited per elastic event**	60 eV	80 keV	400 keV	160 eV	2 eV	0.02 eV
Energy deposited relative to electrons						
(inelastic)	1	400	20	100	100	100
(elastic)	1	1000	10000	2.5	0.03	0.000

Table 1. Energy deposited in biological specimens per useful scattering event

[†] Ratio of inelastic to elastic events for electrons and X-rays are well-known (see, for example, International Tables for crystallography, volume C). The values for neutrons were calculated from neutron scattering cross-sections given by Sears (1992) for the two nuclear reactions ${}^{1}H(n, \gamma) \rightarrow {}^{2}H$ and ${}^{14}N(n, p) \rightarrow {}^{14}C$, which have similar probabilities for typical protein composition. The black dots in Fig. 2 show where these points have been taken from in the overall curve describing the variation with wavelength.

 The 2 keV estimated energy deposited per neutron inelastic event is the average of the deuteron recoil energy in the first reaction (1'3 keV) and the ¹⁴C recoil energy in the second reaction (3 keV). The emitted y-ray and proton in each case carries away a much larger energy but little of this would be deposited in the specimen. With X-ray and electron inelastic events, energy is deposited by the emitted electrons and secondary electrons respectively.

** Row 1 multiplied by Row 3.

Henderson, Quarterly Reviews of Biophysics 28, p. 171 (1995) ELECTRON MICROSCOPY FOR MATERIALS SCIENCE

Averaging identical objects

$$\rho_A \approx \frac{\rho}{\sqrt{M}}$$

- 1. Crystalline: natural average, smaller structures
- 2. 2D, 1D periodic structures
- 3. Oriented objects (laser)
- 4. Random objects (minimal size)



Structure	Resolution	Reference
Two-dimensional crystals		
[high resolution (better than 4 Å)]		
Bacteriorhodopsin p3	3.5 Å, 3.0 Å	Henderson et al. (1990), Kimura et al. (1997)
Plant LHC-II	3-4 Å	Kühlbrandt et al. (1994)
Tubulin dimmer	3.7 Ā	Nogales et al. (1998)
Aquaporin	3·8 Å, 4·0 Å	Murata et al. (2000), Mitra et al. (2002)
Two-dimensional crystals		
[low resolution (better than 9 Å)]		
Bacteriorhodopsin orthorhombic	6.5 Å	Leifer & Henderson (1983)
Deoxycholate bacteriorhodopsin	6-0 Å	Tsygannik & Baldwin (1987)
Halorhodopsin	5-0 Å	Kunji et al. (2000)
Porin PhoÊ	6-0 Å	Jap et al. (1991)
Plant photosystem II RC	8-0 Å	Rhee et al. (1998)
Yeast H ⁺ -ATPase	8-0 Å	Auer et al. (1998)
Gap junction channel	7.5 Å	Unger et al. (1999)
Glutathione transferase	6-0 Å	Schmidt-Krey et al. (2000)
NhaA Na/H antiporter	7.0 Å	Williams (2000)
Glycerol channel GlpF	6-9 Å	Stahlberg et al. (2000)
Rhodopsin, frog p2	7.5 Å	Unger et al. (1997)
Rhodopsin, bovine p22121	5.5 Å	Krebs et al. (2003)
OxIT, oxalic acid transporter	6.5 Å	Hirai et al. (2002)
SecYEG complex	8-0 Å	Breyton et al. (2002)
EmrE multidrug transporter	7.0 Å	Ubarretxena-Belandia et al. (2003)
Helical structures		
Acetylcholine receptor	4.0 Å	Miyazawa et al. (2003)
Bacterial flagellum	4-0 Å	Yonekura et al. (2003)
Microtubule	8-0 Å	Li et al. (2002)
Calcium ATPase	8-0 Å	Zhang et al. (1998)
Tobacco mosaic virus	10-0 Å	Jeng et al. (1989)

Table 1. 2D and 1D structures beyond 10 Å resolution

Henderson, Quarterly Reviews of Biophysics 37, p. 3 (2004)

Structure	MW^a	Resolution	Reference
Icosahedral structures			
Hepatitis B cores	4·1 MDa	7·4 Å, 9 Å	Böttcher <i>et al.</i> (1997), Conway <i>et al.</i> (1997)
Herpes virus capsid	192 MDa	8∙5 Å	Zhou et al. (2000)
Cytoplasmic polyhedrosis virus	>40 MDa	8 Å	Zhou et al. (2003)
Semliki Forest virus	48 MDa	9 Å ^ь	Mancini et al. (2000)
PM2 virus	47 MDa	8∙5 Å	Huiskonen et al. (In Press)
Sindbis virus	46 MDa	∼11 Å	Zhang et al. (2002)
Dengue virus	>13 MDa	9∙5 Å	Zhang et al. (2003a)
Reovirus virions	110 MDa	7.6 Å	Zhang et al. (2003b)
Pyruvate dehydrogenase, E2CD	1.5 MDa	8.7 Å	Rosenthal & Henderson (2003)
Rice dwarf virus	53 MDa	6·8 Å	Zhou et al. (2001)
Tomato bushy stunt virus	8.9 MDa	5.9 Ű	van Heel et al. (2000)
P22 bacteriophage mature/shell	50/20 MDa	9∙5/8∙5 Å	Jiang et al. (2003)
Single particles of lower ^d symmetry than icosahedral			
E. coli 708 ribosome	2·5 MDa	11·5 Å, 9 Å	Gabashvili <i>et al.</i> (2000), Valle <i>et al.</i> (2003)
Bacteriophage SPP1 connectors	1.0 MDa	10 Å	Orlova et al. (2003)
50S ribosomal subunit	1∙6 MDa	7.5 Å ^e	Matadeen et al. (1999)
GroEL	0.8 MDa	8·7 Å, 11·5 Å	Ranson <i>et al.</i> (2001), Ludtke <i>et al.</i> (2001)

Table 2. Single particle structures beyond 10 \mathring{A} resolution

Henderson, Quarterly Reviews of Biophysics 37, p. 3 (2004)

What is the best that has been done by cryo -TEM methods ? (not 2D xtals)

Protein synthesis ("Life itself") in the Ribosome: The ribosome structure determined to 1nm resolution by TEM (tomographic cryomicroscopy). J.Frank et al.



Experimental e-coli ribsome reconstruction from TEM images of non-crystallised mols in ice. mRNA bring 3-bit codons from DNA. tRNA "adaptors" (E,P,A) have plugs at one end to mRNA codon, at the other to an amino acid, which is added to the polypetide chain as the ribo runs along the mRNA. Chain will fold to become a new protein. (Simplified)

Courtesy J. Spence

Source brightness

- □ X-rays
 - New generation synchrotrons
 - Free Electron Laser Source (FELS)
 - Bosons (NO fundamental limit)
- Electrons
 - Field emission sources
 - Correctors
 - Fermions: limit of phase space (still 10⁵ off)
 - Coulomb interaction



TABLE 1. Comparison of synchrotron soft X-ray and field-emission electron sources. All values are for 500 eV X-rays, or the 300 keV electron beams which are typically used to study ELNES at around 500 eV. ELNES uses parallel detection, XANES serial.

	ALS Undulator U5	e ⁻ Cold FEG at 300 k V
 Brightness	6.9 X 10 ²⁴ particles /sec	1.3×10^{29} particles /sec /cm ² /sr
	$/\mathrm{cm}^2/\mathrm{sr}/\mathrm{eV}$	/eV
	$(1.1 \text{ X } 10^{19} \text{ Ph/s /mm}^2)$	$(6 \times 10^{9} \text{ A/cm}^{2} / \text{sr.})$
	/mr ² / 0.1%BW)*	
 Degeneracy δ	18	1.54 X 10 ⁻⁵
Coherent flux j _c	2.0 X 10 ⁷	
	ph/s/0.1%BW	
Energy spread	4.6 eV	0.28 eV
ΔE (un-monochromated).		
Source size.	307x23 µm	2nm
Resolution of focussing	30 nm	0.1 nm
element.		
Flux into focussed probe	4.0×10^5	1nA into 1nm diameter.
	ph/s/0.1%BW	Higher with aberration corrector.

* This is the long time average value. Instantaneous values are about D=100 times greater

Electron brightness values from Speidel et al Optik 49, 173. Nanotip at RT is 55 times brighter (Qian, Scheinfein, Spence J.Appl Phys.73, p.7041.

Spence and Howells, Ultramic.93, p.213 (2003) ELECTRON MICROSCOPY FOR MATERIALS SCIENCE

Scanning Electron Microscopy & HREM & Spectroscopy

A STEM / HRTEM : Tecnai G²







Upgrade to HRTEM/STEM @ NCEM in 2002 First instrument of this kind in the US

Probe size 0.13 nm (currently at NCEM: ~1 nm)
Energy resolution: 200 - 300 meV (currently: ~1eV)
Information Limit : < 0.1 nm @ 200 kV
Phase Contrast & Z-Contrast & Spectroscopy on identical areas *N. Browning, C. Kisielowski, LDRD, 2002-2003*

We are entering a new era in x-ray science



This short-pulse high-fluence x-ray regime is completely unexplored. What ever we do with these sources will be new science



Combine damage and classification results to determine the required pulse parameters

Preliminary Results



Maximum Pulse Length versus Radius, Resolution, and Sample Size; Limited by Classification <u>and</u> Damage (R_{max} = 0.25)

- Resolution from damage modeling worsens with increasing fluence and increasing pulse length
- For a given radius and fluence, we can determine the maximum pulse length

Courtesy H. Chapman

Atomic resolution can be achieved for optimized XFEL parameters (short pulses, high fluences)

Resolution - precision



EXAMPLE: coherent HREM better than HAADF STEM





Precision:

Cramér-Rao Lower Bound

$$\sigma_{_{CR}} = rac{
ho}{\sqrt{\delta\sigma_{_{el}}}}$$

 $\begin{cases} \rho = \text{resolution} \\ \delta = \text{incident dose}/\text{Å}^2 \\ \sigma_{el} = \text{elastic cross section} \end{cases}$

Probability for displacive damage of an atom:

 $p = \delta \sigma_{in} \qquad \sigma_{in} = \text{inelastic cross section}$ Figure of merit $\longrightarrow \qquad \sigma_{CR}^2 p = \rho^2 \frac{\sigma_{in}}{\sigma_{el}}$



 $\sigma_{el} = \int \left| \frac{2\pi e V_p(r)}{E\lambda} \right|^2 d\bar{r}$

 $\begin{cases} V_p(\bar{r}) = \text{projected potential} \\ E = \text{incident electron energy} \\ \lambda = \text{electron wavelength} \end{cases}$

$$\sigma_{in} = \pi \left(\frac{\alpha}{2E}\right)^2 \left(\frac{T}{\varepsilon} - 1\right)^2$$
$$\alpha = \frac{Ze^2}{4\pi\varepsilon_0}$$
$$T = \frac{4m}{M}E$$

- Z = atom number
- m = electron mass
- M =atom mass
- ε = threshold energy for

displacive radiation damage



Simple model

$$\sigma_{CR}^2 p = c \left[\frac{1}{1000Z\varepsilon} - \frac{1}{E} \right]$$

With Z = atomic number E = incident energy (eV) $\epsilon = \text{treshold energy for displacement damage}$





Experimental design

At low accelerating voltages:

- Do we need a Cs-corrector?
- Do we need a Cc-corrector?
- Do we need a monochromator?



Precision of a Si atom position as a function of Cs Accelerating voltage = 50 keV





Conclusion

- Both electron and X-ray methods can ultimately resolve individual atoms.
- Quantitative refinement can yield precisions that are needed for theoretical understanding.

